

Notice of References Cited	Application/Control No. 10/556,729		Applicant(s)/Patent Under Reexamination KIKKOJI ET AL.	
	Examiner EMILE SU		Art Unit 3685	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,038,434 A	03-2000	Miyake, Takashi	455/186.1
*	B	US-6,205,419 B1	03-2001	Fiedler, Mark	704/201
*	C	US-6,505,160 B1	01-2003	Levy et al.	704/270
*	D	US-6,912,431 B2	06-2005	Kim et al.	700/83
*	E	US-7,171,174 B2	01-2007	Ellis et al.	455/132
*	F	US-7,164,882 B2	01-2007	Poltorak, Alexander I.	455/3.06
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE, "IEEE 100: the authoritative dictionary of IEEE standards terms", seventh edition, pp. 204, 684, 934, 1112, 1234, 1235. Published December 2000.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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